Notice of References Cited Application/Control No. 10/707,218 Applicant(s)/Patent Under Reexamination HSUAN, JOHN Examiner Tanh Q. Nguyen Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,906,699 B1	06-2005	Fåhraeus et al.	345/157
*	В	US-7,113,206 B2	09-2006	Nakakuki, Toshio	348/222.1
*	С	US-5,140,148 A	08-1992	Kitamura et al.	250/208.1
*	D	US-6,375,075 B1	04-2002	Ackley et al.	235/462.04
*	Ε	US-6,710,768 B2	03-2004	Muranami, Masahiko	345/166
*	F	US-6,844,871 B1	01-2005	Hinckley et al.	345/163
*	G	US-2002/0044134 A1	04-2002	Ericson et al.	345/163
*	н	US-2001/0035861 A1	11-2001	Ericson et al.	345/179
*	1	US-5,920,063 A	07-1999	Kawamoto et al.	250/208.1
*	J	US-6,407,830 B1	06-2002	Keithley et al.	358/514
*	к	US-5,994,710 A	11-1999	Knee et al.	250/557
*	L	US-2002/0154215 A1	10-2002	Schechterman et al.	348/51
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.